- Each Device Drives 12 Lines
- 60-V Output Voltage Swing Capability
- 25-mA Output Source Current Capability
- High-Speed Serially-Shifted Data Input
- TTL-Compatible Inputs
- Latches on All Driver Outputs


## description

The SN65512B and SN75512B are monolithic BIDFET $\dagger$ integrated circuits designed to drive a dot matrix or segmented vacuum fluorescent display.
All device inputs are diode-clamped pnp inputs and assume a high logic level when open circuited. The nominal input threshold voltage is 1.5 V . Outputs are totem-pole structures formed by an npn emitter-follower and double-diffused MOS (DMOS) transistors.

The device consists of a 12-bit shift register, 12 latches, and 12 output AND gates. Serial data is entered into the shift register on the low-to-high transition of CLOCK. When high, LATCH ENABLE transfers the shift register contents to the outputs of the 12 latches. The active-low STROBE input enables all Q outputs. Serial data output from the shift register can be used to cascade shift registers. This output is not affected by LATCH ENABLE or STROBE.

The SN65512B is characterized for operation from $-40^{\circ} \mathrm{C}$ to $85^{\circ} \mathrm{C}$. The $\mathrm{SN75512B}$ is characterized for operation from $0^{\circ} \mathrm{C}$ to $70^{\circ} \mathrm{C}$.


## logic symbol $\ddagger$



[^0]
## logic diagram (positive logic)



FUNCTION TABLE

| FUNCTION | CONTROL INPUTS |  |  | SHIFT REGISTER R1 THRU R12 | LATCHES LC1 THRU LC12 | OUTPUTS |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | CLOCK | LATCH ENABLE | STROBE |  |  | SERIAL | Q1 THRU Q12 |
| Load | $\uparrow$ No $\uparrow$ | X | X | Load and shift $\dagger$ No change | Determined by LATCH ENABLE $\ddagger$ | R12 | Determined by STROBE |
| Latch | X | L $H$ | X | As determined above | Stored data New data | R12 | Determined by STROBE |
| Strobe | X | X | $\begin{aligned} & \mathrm{H} \\ & \mathrm{~L} \end{aligned}$ | As determined above | Determined by LATCH ENABLE $\ddagger$ | R12 | All LC <br> LC1 thru LC12, respectively |

[^1]typical operating sequence

schematics of inputs and outputs


## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

| Supply voltage range, $\mathrm{V}_{\text {CC1 }}$ (see Note 1) |  |
| :---: | :---: |
| Supply voltage, $\mathrm{V}_{\text {CC2 }}$ | 70 V |
|  |  |
| Continuous total power dissipation ................................. See Dissipation Rating Table |  |
| Operating free-air temperature range, $\mathrm{T}_{\mathrm{A}}$ : $\mathrm{SN65512B}$ | $-40^{\circ} \mathrm{C}$ to $85^{\circ} \mathrm{C}$ |
| SN75512B | $0^{\circ} \mathrm{C}$ to $70^{\circ} \mathrm{C}$ |
| Storage temperature range, $\mathrm{T}_{\text {stg }}$ | $-65^{\circ} \mathrm{C}$ to $150^{\circ} \mathrm{C}$ |
| Lead temperature 1,6 mm (1/16 inch) from case | $260^{\circ}$ |

NOTES: 1. Voltage values are with respect to network ground terminal.
DISSIPATION RATING TABLE

| PACKAGE | $\mathrm{T}_{\mathrm{A}} \leq 25^{\circ} \mathrm{C}$ <br> POWER RATING | DERATING FACTOR ABOVE TA $=25^{\circ} \mathrm{C}$ | $\mathrm{T}_{\mathrm{A}}=70^{\circ} \mathrm{C}$ <br> POWER RATING | $\mathrm{T}_{\mathrm{A}}=125^{\circ} \mathrm{C}$ <br> POWER RATING |
| :---: | :---: | :---: | :---: | :---: |
| DW | 1125 mW | $9.0 \mathrm{~mW} /{ }^{\circ} \mathrm{C}$ | 720 mW | 585 mW |
| N | 1150 mW | $9.2 \mathrm{~mW} /{ }^{\circ} \mathrm{C}$ | 736 mW | 589 mW |

recommended operating conditions

|  |  |  | SN65512B |  | SN75512B |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | MIN | MAX | MIN | MAX |  |
| Supply voltage, $\mathrm{V}_{\mathrm{CC} 1}$ |  |  | 5 | 15 | 5 | 15 | V |
| Supply voltage, $\mathrm{V}_{\mathrm{CC} 2}$ |  |  | 0 | 60 | 0 | 60 | V |
| High-level input voltage, $\mathrm{V}_{\mathrm{IH}}$ |  |  | 2 |  | 2 |  | V |
| Low-level input voltage, $\mathrm{V}_{\mathrm{IL}}$ |  |  |  | 0.8 |  | 0.8 | V |
| High-level output current, IOH |  |  |  | -25 |  | -25 | mA |
| Low-level output current, IOL | $\mathrm{V}_{\mathrm{CC} 1}=10 \mathrm{~V}$ |  |  | 5 |  | 5 | mA |
| Clock frequency, $\mathrm{f}_{\text {clock }}$ | $\mathrm{V}_{\mathrm{CC} 1}=15 \mathrm{~V}$, | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ | 0 | 4 | 0 | 4 | MHz |
|  | $\mathrm{V}_{\mathrm{CC} 1}=5 \mathrm{~V}$, | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ | 0 | 1 | 0 | 1 |  |
| Pulse duration, CLOCK high or low, $\mathrm{t}_{\mathrm{w}}$ | $\mathrm{V}_{\mathrm{CC} 1}=15 \mathrm{~V}$, | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ | 100 |  | 100 |  | ns |
|  | $\mathrm{V}_{\mathrm{CC} 1}=5 \mathrm{~V}$, | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ | 500 |  | 500 |  |  |
| Setup time, DATA IN valid before CLOCK $\uparrow$, $\mathrm{t}_{\text {su }}$ (see Figure 1) | $\mathrm{V}_{\mathrm{CC} 1}=15 \mathrm{~V}$, | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ | 100 |  | 100 |  | ns |
|  | $\mathrm{V}_{\mathrm{CC} 1}=5 \mathrm{~V}$, | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ | 250 |  | 250 |  |  |
| Hold time, DATA IN valid after CLOCK $\uparrow$, th (see Figure 1) | $\mathrm{V}_{\mathrm{CC} 1}=15 \mathrm{~V}$, | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ | 50 |  | 50 |  | ns |
|  | $\mathrm{V}_{\mathrm{CC} 1}=5 \mathrm{~V}$, | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ | 250 |  | 250 |  |  |
| Operating free-air temperature, $\mathrm{T}_{\mathrm{A}}$ |  |  | -40 | 85 | 0 | 70 | ${ }^{\circ} \mathrm{C}$ |

electrical characteristics over recommended operating free-air temperature range, $\mathrm{V}_{\mathrm{CC} 2}=60 \mathrm{~V}$ (unless otherwise noted)

| PARAMETER |  |  | TEST CONDITIONS |  | MIN | TYP $\dagger$ | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {IK }}$ | Input clamp voltage |  | $\mathrm{I}=-12 \mathrm{~mA}$ |  |  |  | -1.5 | V |
| VOH | High-level output voltage | Q outputs | $\mathrm{IOH}=-25 \mathrm{~mA}$, | $\mathrm{V}_{\mathrm{CC} 1}=10 \mathrm{~V}$ | 57.5 | 58 |  | V |
|  |  | SERIAL OUT | $\mathrm{I}^{\mathrm{OH}}=-200 \mu \mathrm{~A}$, | $\mathrm{V}_{\mathrm{CC} 1}=10 \mathrm{~V}$ | 9 | 9.5 |  |  |
| $\mathrm{V}_{\mathrm{OL}}$ | Low-level output voltage | Q outputs | $\mathrm{IOL}=5 \mathrm{~mA}$, | $\mathrm{V}_{\mathrm{CC} 1}=10 \mathrm{~V}$ |  | 2.6 | 5 | V |
|  |  | SERIAL OUT | $\mathrm{IOL}=200 \mu \mathrm{~A}$, | $\mathrm{V}_{\mathrm{CC} 1}=10 \mathrm{~V}$ |  | 0.05 | 0.2 |  |
| IIH | High-level input current |  | $\mathrm{V}_{\mathrm{CC} 1}=15 \mathrm{~V}$, | $\mathrm{V}_{\mathrm{I}}=5 \mathrm{~V}$ |  | 0.01 | 1 | $\mu \mathrm{A}$ |
| IIL | Low-level input current |  | $\mathrm{V}_{\mathrm{CC} 1}=15 \mathrm{~V}$, | $\mathrm{V}_{1}=0.8 \mathrm{~V}$ |  | -25 | -150 | $\mu \mathrm{A}$ |
| ${ }^{\text {ICC1 }}$ | Supply current from $\mathrm{V}_{\mathrm{CC} 1}$ |  | $\mathrm{V}_{\mathrm{CC} 1}=15 \mathrm{~V}$ | $\mathrm{V}_{\mathrm{I}}=5 \mathrm{~V}$ |  | 80 | 500 | $\mu \mathrm{A}$ |
|  |  |  | $\mathrm{V}_{1}=0.8 \mathrm{~V}$ |  | 2 | 6 | mA |  |
| ICC2 | Supply current from $\mathrm{V}_{\mathrm{CC} 2}$ |  |  | $\mathrm{V}_{\mathrm{CC} 1}=15 \mathrm{~V}$ | All outputs high |  | 10 | 100 | $\mu \mathrm{A}$ |
|  |  |  | STROBE at 2 V |  |  | 0.8 | 3 | mA |

$\dagger$ All typical values are at $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$.
switching characteristics, $\mathrm{V}_{\mathrm{CC} 1}=10 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC} 2}=60 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$

| PARAMETER | TEST CONDITIONS | MIN MAX | UNIT |
| :---: | :---: | :---: | :---: |
| tPHL Propagation delay time, high-to-low level output | $C_{L}=30 \mathrm{pF}, \quad$ See Figure 2 | 300 | ns |
| tPLH Propagation delay time, low-to-high level output |  | 300 | ns |
| tTHL Transition time, high-to-low level output |  | 500 | ns |
| tTLH Transition time, low-to-high level output |  | 500 | ns |

## PARAMETER MEASUREMENT INFORMATION



Figure 1. Input Timing Voltage Waveforms


Figure 2. Switching Time Voltage Waveforms

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[^0]:    $\ddagger$ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

[^1]:    $\mathrm{H}=$ high level, $\mathrm{L}=$ low level, $\mathrm{X}=$ irrelevant, $\uparrow=$ low-to-high-level transition
    $\dagger$ R12 takes on the state of R11, R11 takes on the state of R10, . . R2 takes on the state of R1, and R1 takes on the state of the data input.
    $\ddagger$ New data enter the latches while LATCH ENABLE is high. These data are stored while LATCH ENABLE is low.

